

General Description:

The GL200N06A0 uses advanced trench technology and design to provide excellent RDS(ON) with low gate charge. It can be used in a wide variety of applications. The package form is TO-263, which accords with the RoHS standard.

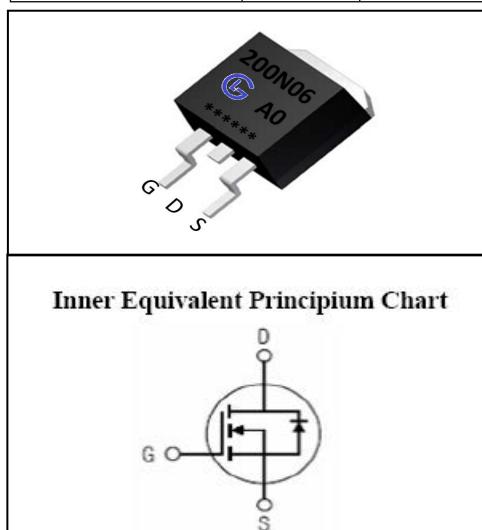
Features:

- Fast Switching
- Low Gate Charge and Rdson
- Low Reverse transfer capacitances
- 100% Single Pulse avalanche energy Test

Applications:

Power switching application
Hard switched and high frequency circuits
Uninterruptible power supply

V _{DSS}	60	V
I _D	200	A
P _D	250	W
R _{DS(ON)type}	3.3	mΩ



Absolute (T_c= 25 °C unless otherwise specified):

Symbol	Parameter	Rating	Units
V _{DSS}	Drain-to-Source Voltage	60	V
I _D	Continuous Drain Current	200	A
	Continuous Drain Current T _c = 100 °C	160	A
I _{DM}	Pulsed Drain Current	800	A
V _{GS}	Gate-to-Source Voltage	± 20	V
E _{AS} a2	Single Pulse Avalanche Energy	600	mJ
E _{AR} a1	Avalanche Energy ,Repetitive	80	mJ
I _{AR} a1	Avalanche Current	96	A
dv/dt a3	Peak Diode Recovery dv/dt	5.0	V/ns
P _D	Power Dissipation	250	W
T _J , T _{stg}	Operating Junction and Storage Temperature Range	175, -55 to 175	°C
T _L	MaximumTemperature for Soldering	300	°C



GL200N06A0

GL Silicon N-Channel Power MOSFET

Electrical Characteristics ($T_c = 25^\circ C$ unless otherwise specified):

OFF Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
V_{DSS}	Drain to Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	60	--	--	V
$\Delta BV_{DSS}/\Delta T_J$	Bvdss Temperature Coefficient	$I_D=250\mu A$, Reference $25^\circ C$	--	0.1	--	$V/^\circ C$
I_{DSS}	Drain to Source Leakage Current	$V_{DS} = 60V, V_{GS} = 0V, T_a = 25^\circ C$	--	--	1	μA
		$V_{DS} = 48V, V_{GS} = 0V, T_a = 125^\circ C$	--	--	250	
$I_{GSS(F)}$	Gate to Source Forward Leakage	$V_{GS} = +20V$	--	--	1	μA
$I_{GSS(R)}$	Gate to Source Reverse Leakage	$V_{GS} = -20V$	--	--	-1	μA

ON Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$R_{DS(ON)}$	Drain-to-Source On-Resistance	$V_{GS}=10V, I_D=100A$	--	3.3	3.6	$m\Omega$
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu A$	2.0	--	4.0	V
Pulse width $t_p \leqslant 380\mu s, \delta \leqslant 2\%$						

Dynamic Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
g_{fs}	Forward Transconductance	$V_{DS}=5V, I_D=50A$	120	--	--	S
C_{iss}	Input Capacitance		--	8000	--	pF
C_{oss}	Output Capacitance	$V_{GS} = 0V, V_{DS} = 30V, f = 1.0MHz$	--	1200	--	
C_{rss}	Reverse Transfer Capacitance		--	90	--	

Resistive Switching Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$t_{d(ON)}$	Turn-on Delay Time	$I_D = 60A, V_{DD} = 30V, V_{GS} = 10V, R_G = 2.5\Omega$	--	26	--	ns
tr	Rise Time		--	25	--	
$t_{d(OFF)}$	Turn-Off Delay Time		--	120	--	
t_f	Fall Time		--	36	--	
Q_g	Total Gate Charge	$I_D = 60A, V_{DD} = 30V, V_{GS} = 10V$	--	150	--	nC
Q_{gs}	Gate to Source Charge		--	30	--	
Q_{gd}	Gate to Drain ("Miller")Charge		--	20	--	

Source-Drain Diode Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
I _S	Continuous Source Current (Body Diode)		--	--	200	A
I _{SM}	Maximum Pulsed Current (Body Diode)		--	--	800	A
V _{SD}	Diode Forward Voltage	I _S =100A, V _{GS} =0V	--	--	1.5	V
t _{rr}	Reverse Recovery Time	I _S =100A, T _j = 25 ° C	--	90	--	ns
Q _{rr}	Reverse Recovery Charge	dI _F /dt=100A/us, V _{GS} =0V	--	15 0	--	nC
Pulse width tp≤380μs, δ ≤2%						

Symbol	Parameter	Typ.	Units
R _{θ C}	Junction-to-Case	1.8	°C /W

^{a1}: Repetitive rating; pulse width limited by maximum junction temperature

^{a2}: EAS condition : T_j=25 ° C ,V_{DD}= 30V,V_G=10V,L=0.5mH,R_g=25Ω

^{a3}: I_{SD}=100A,di/dt ≤100A/us,V_{DD}≤BV_{DS}, Start T_j=25 ° C

Test Circuit and Waveform

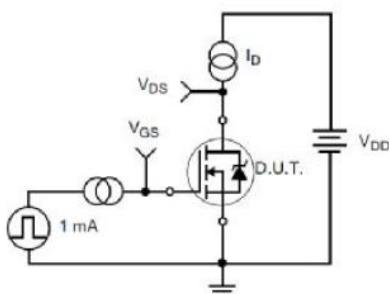


Figure 17. Gate Charge Test Circuit

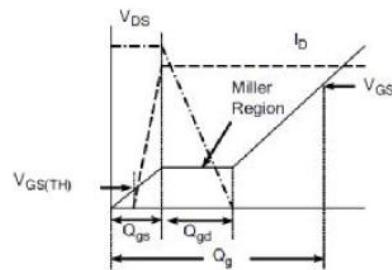


Figure 18. Gate Charge Waveform

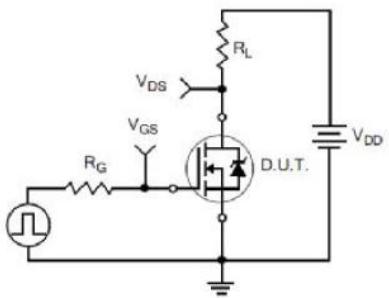


Figure 19. Resistive Switching Test Circuit

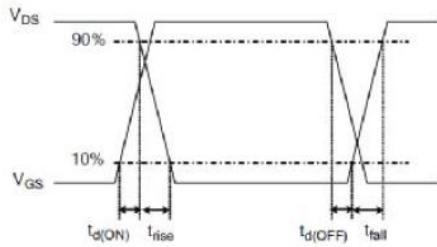


Figure 20. Resistive Switching Waveforms